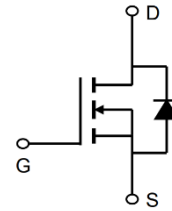


20V N-Channel Enhancement Mode MOSFET

Description

The AP40N02D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

$V_{DS} = 20V$ $I_D = 40A$

$R_{DS(ON)} < 10m\Omega$ @ $V_{GS}=10V$

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP40N02D	TO-252-3L	AP40N02D XXXX YYYY	2500

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Limit	Unit
V_{DS}	Drain-Source Voltage	20	V
V_{GS}	Gate-Source Voltage	± 12	V
I_D	Drain Current-Continuous	40	A
$I_D(100^\circ C)$	Drain Current-Continuous($T_C=100^\circ C$)	28	A
I_{DM}	Pulsed Drain Current	80	A
P_D	Maximum Power Dissipation	40	W
E_{AS}	Single pulse avalanche energy (Note 5)	150	mJ
T_J, T_{STG}	Operating Junction and Storage Temperature Range	-55 To 150	$^\circ C$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 2)	3.8	$^\circ C/W$

20V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_A=25°C unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	20	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =20V, V _{GS} =0V	-	-	1	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±12V, V _{DS} =0V	-	-	±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	0.5	0.7	1.2	V
R _{DS(ON)}	Drain-Source On-State Resistance	V _{GS} =4.5V, I _D =25A	-	6.2	10	mΩ
R _{DS(ON)}	Drain-Source On-State Resistance	V _{GS} =2.5V, I _D =10A	-	9.1	12	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =20A	10	-	-	S
C _{iss}	Input Capacitance	V _{DS} =10V, V _{GS} =0V, F=1.0MHz		1100		PF
C _{oss}	Output Capacitance			162		PF
C _{rss}	Reverse Transfer Capacitance			105		PF
t _{d(on)}	Turn-on Delay Time	V _{GS} =10V, V _{DS} =10V RL=0.5Ω, RGEN=3Ω	-	4.5	-	nS
t _r	Turn-on Rise Time		-	9.2	-	nS
t _{d(off)}	Turn-Off Delay Time		-	18.7	-	nS
t _f	Turn-Off Fall Time		-	3.3	-	nS
Q _g	Total Gate Charge	V _{GS} =10V, V _{DS} =10V, I _D =20A		15		nC
Q _{gs}	Gate-Source Charge			1.8		nC
Q _{gd}	Gate-Drain Charge			2.8		nC
V _{SD}	Diode Forward Voltage ^(Note 3)	V _{GS} =0V, I _S =20A	-	-	1.2	V
I _S	Diode Forward Current ^(Note 2)	-	-	-	30	A
t _{rr}	Reverse Recovery Time	T _J = 25°C, I _F = 20A di/dt = 100A/μs ^(Note3)	-	18	-	nS
Q _{rr}	Reverse Recovery Charge		-	9.5	-	nC
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

- 1、Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2、Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3、Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
- 4、Guaranteed by design, not subject to production
- 5、EAS condition: T_J=25°C, V_{DD}=10V, V_G=10V, L=0.5mH, R_g=25Ω

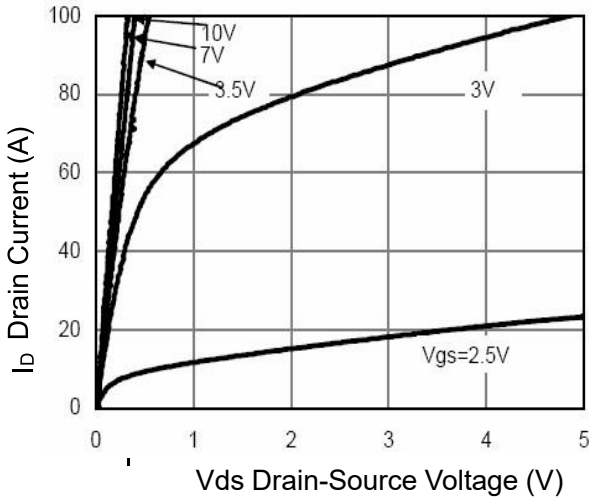


Figure 1 Output Characteristics

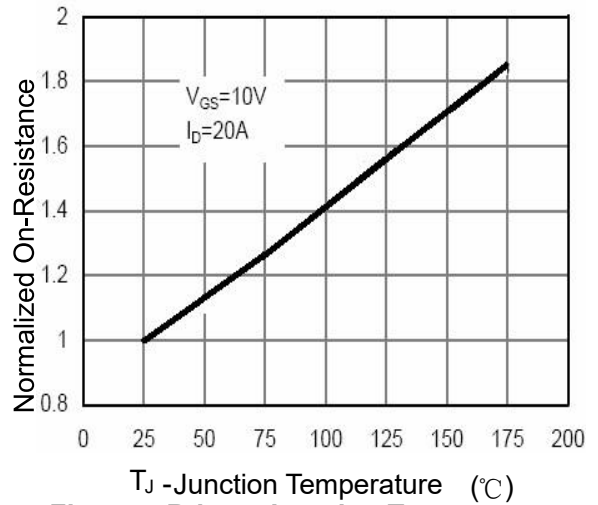


Figure 4 Rdson-Junction Temperature

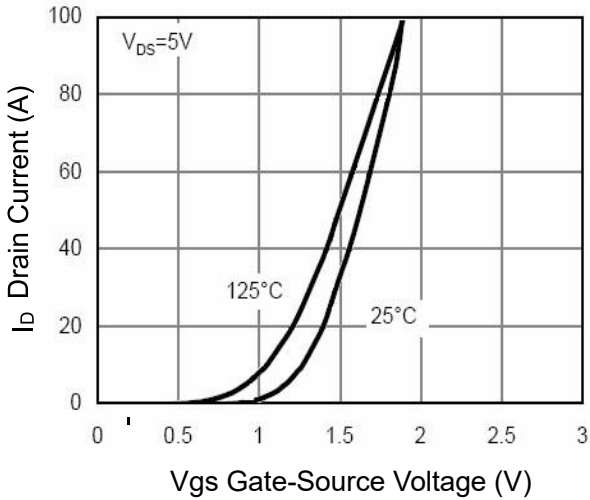


Figure 2 Transfer Characteristics

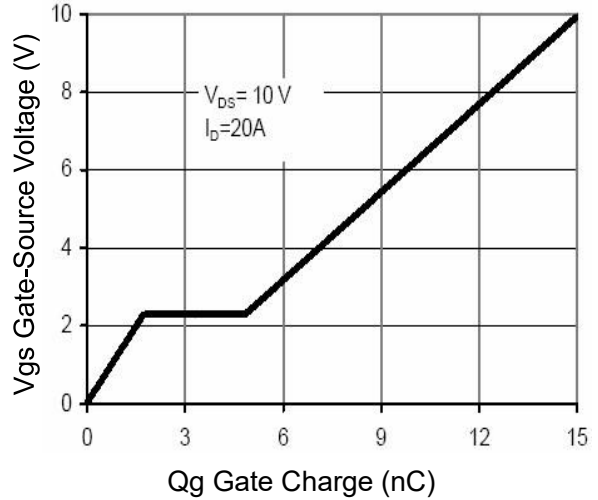


Figure 5 Gate Charge

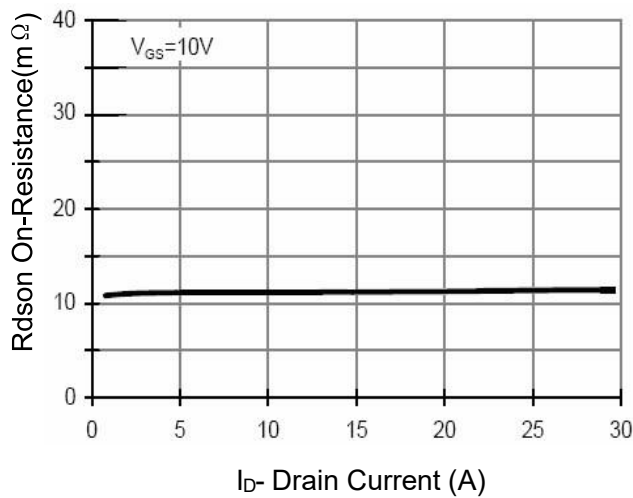


Figure 3 Rdson Drain Current

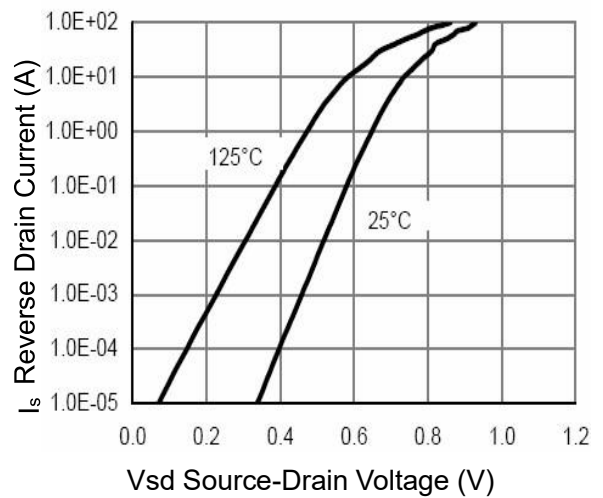
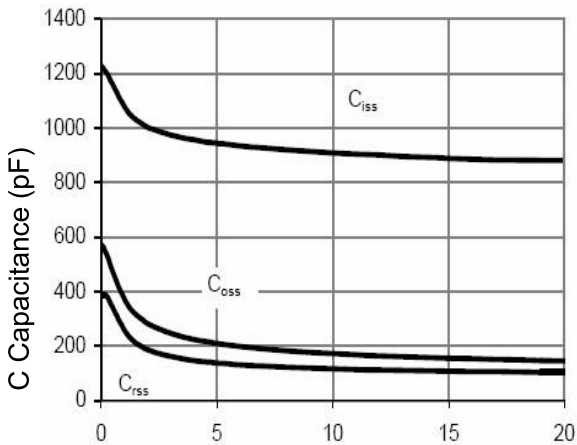
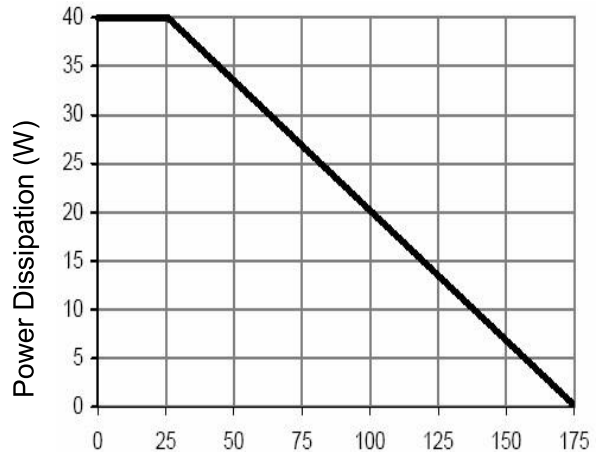


Figure 6 Source-Drain Diode Forward

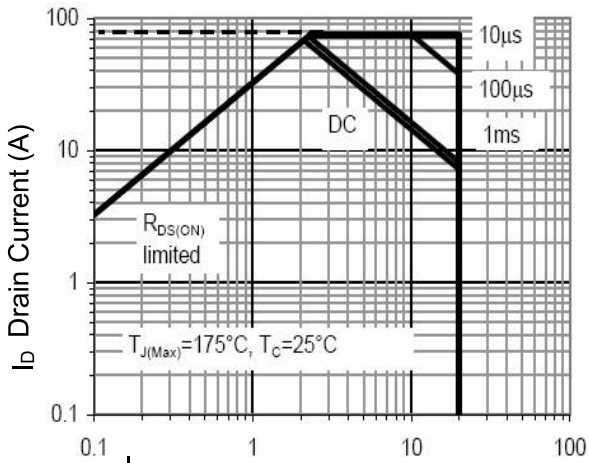
20V N-Channel Enhancement Mode MOSFET



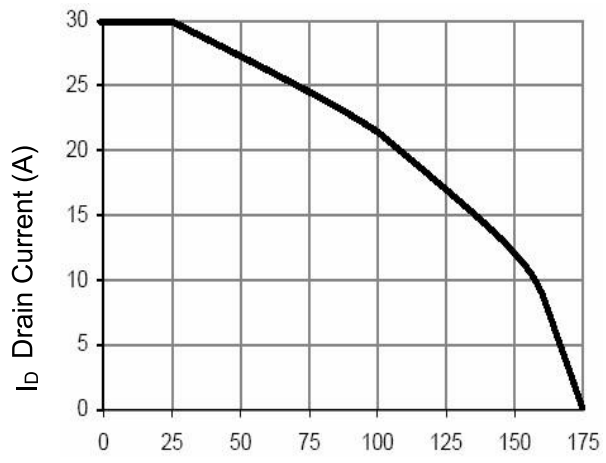
Vds Drain-Source Voltage (V)
Figure 7 Capacitance vs Vds



T_J-Junction Temperature(°C)
Figure 9 Power De-rating



Vds Drain-Source Voltage (V)
Figure 8 Safe Operation Area



T_J-Junction Temperature(°C)
Figure 10 Current De-rating

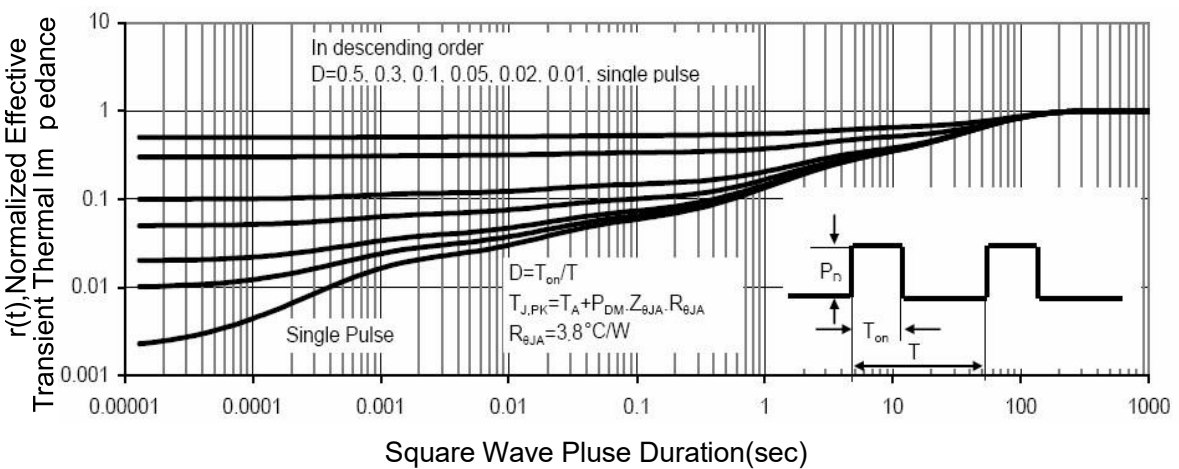
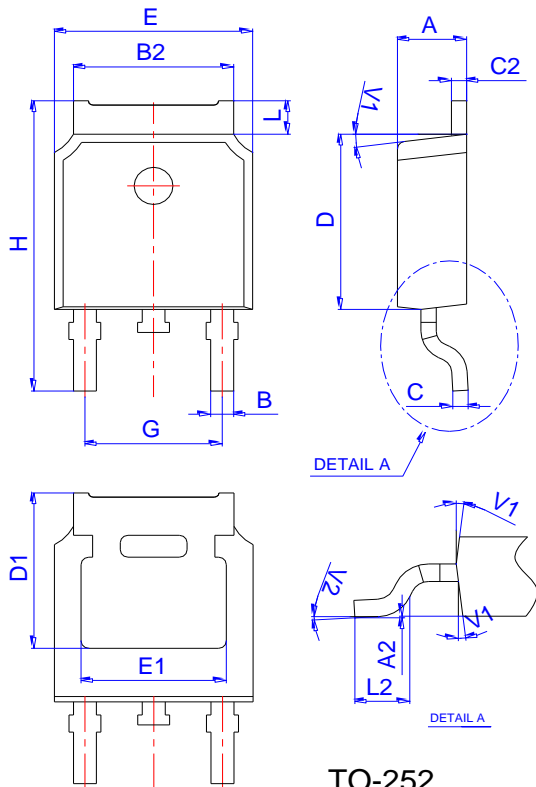


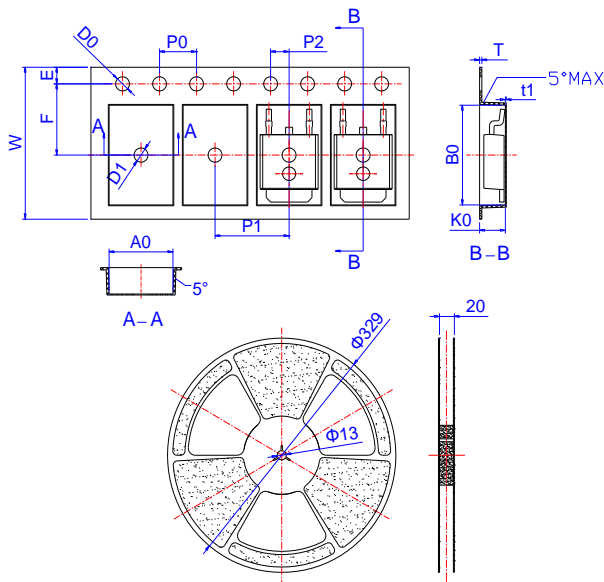
Figure 11 Normalized Maximum Transient Thermal Impedance

Package Mechanical Data:TO-252-3L



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

20V N-Channel Enhancement Mode MOSFET**Attention**

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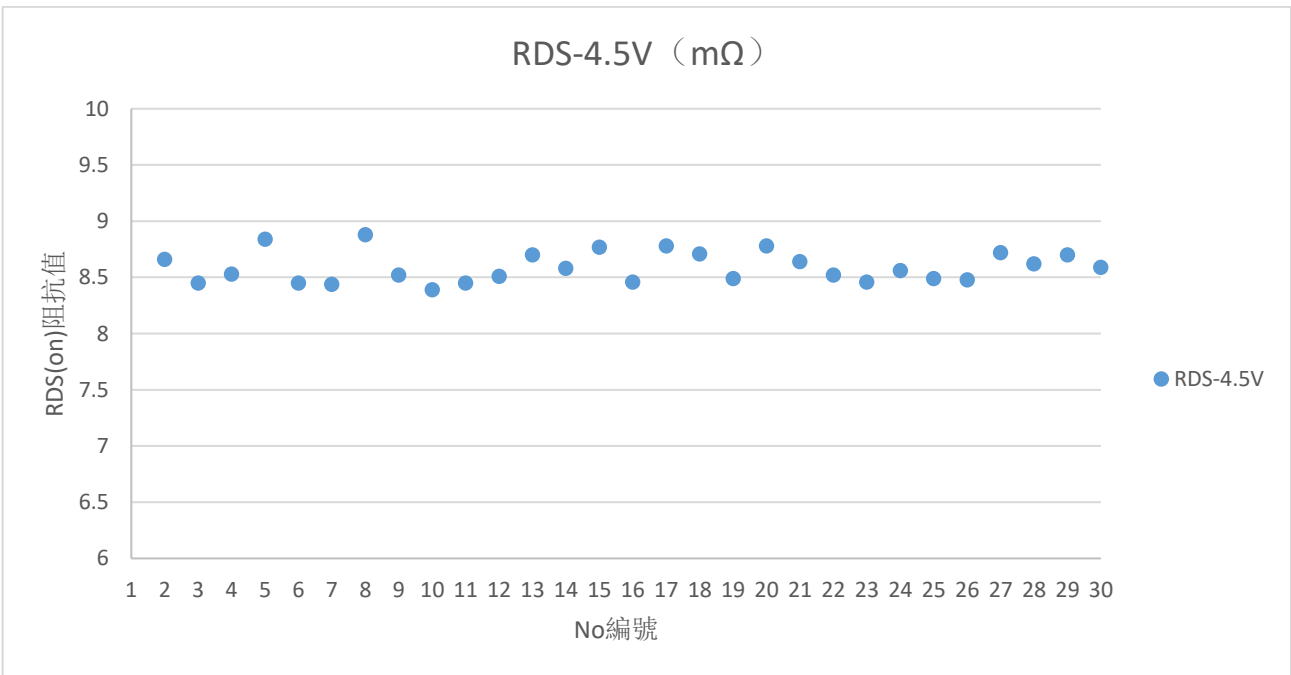
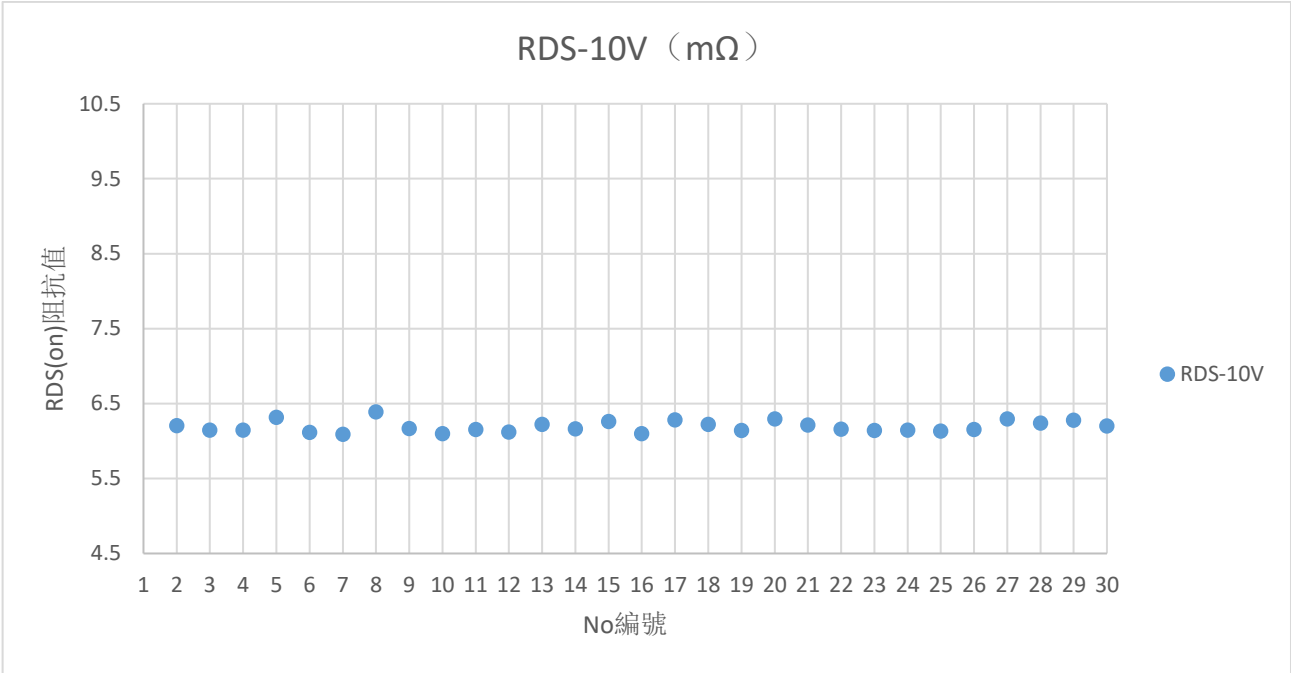
20V N-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve3.2	2018/8/31	Initial release
Rve3.3	2019/11/31	Reduce RDS

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Test Report For 30PCS (30pcs 典型測試報告)





20V N-Channel Enhancement Mode MOSFET

